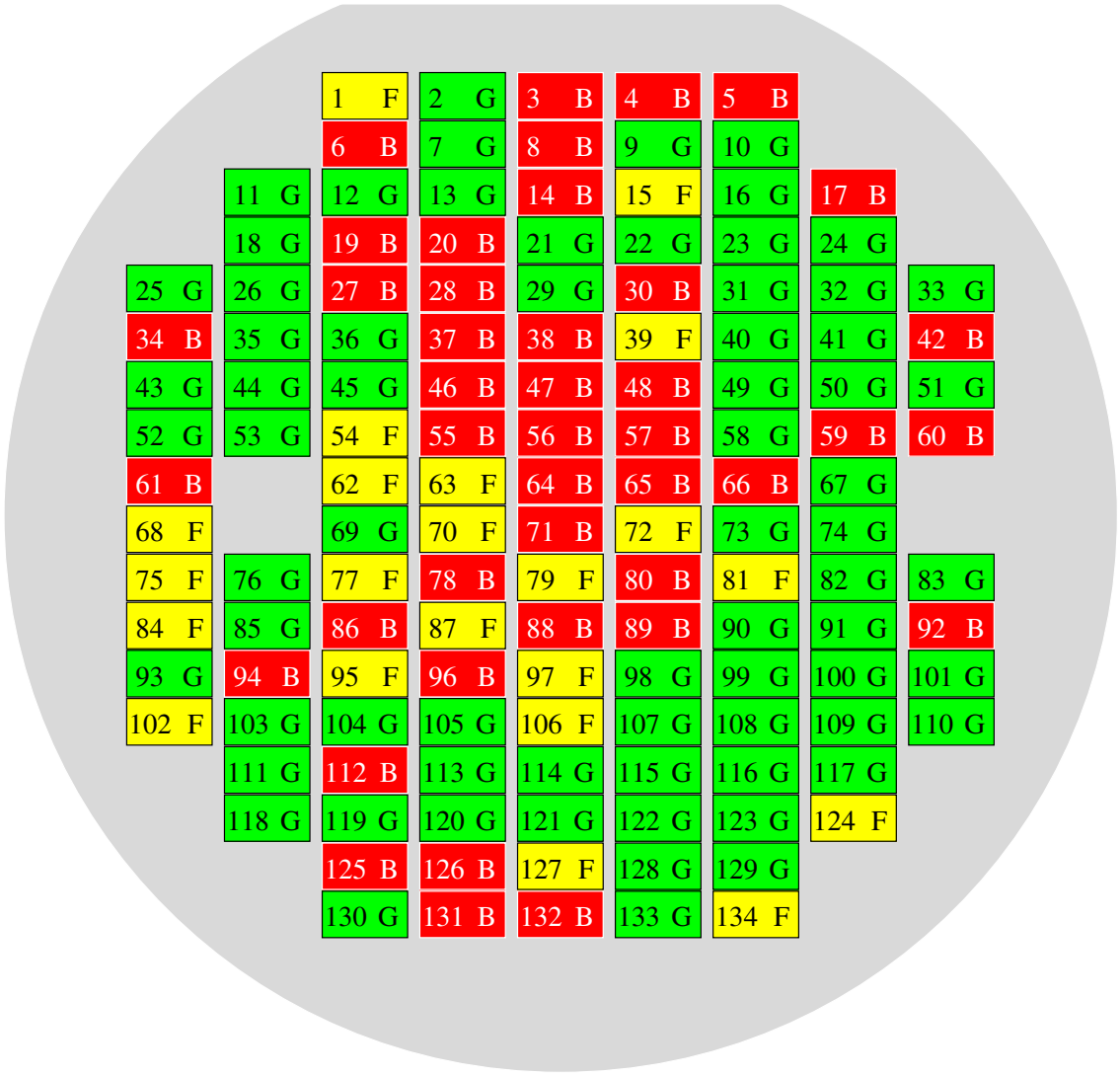
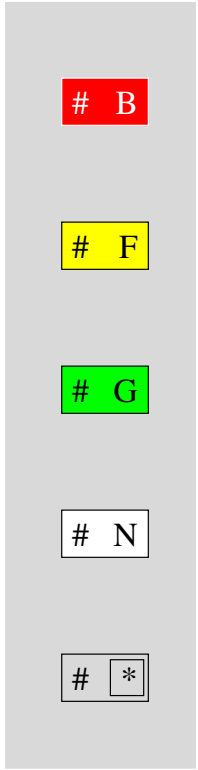
Die quality map for wafer 185 s/n: Y21316-09-07

Date: 07/12/99





Bad die

Fair die

Good die

No info

Manually tagged